

Notice of References Cited

Application/Control No.

10/549,645

Applicant(s)/Patent Under
Reexamination
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Examiner

Zachary Snyder

Art Unit

4135

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,569,970	10-1996	Dynys et al.	313/112
	B	US-			
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	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Advances in X-Ray Analysis Volume 35A edited by Charles S. Barrett et al., Springer, 1992.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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